



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017
& ANSI/NCSL Z540-1-1994

GRAND RAPIDS METROLOGY
4215 Stafford Avenue, SW
Grand Rapids, MI 49548
Danny Thomas Phone: 800 348 5701

CALIBRATION

Valid To: November 30, 2023

Certificate Number: 1489.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations^{1, 7}:

I. Dimensional

Parameter/Equipment	Range	CMC ^{2, 4} (\pm)	Comments
Angle Blocks	Up to 90°	0.02°	Optical comparator
Calipers ³	Up to 24 in (< 24 to 60) in	(300 + 10L) μ in (1400 + 1.2L) μ in	Gage blocks
Cylindrical Discs/Plugs/Pins	Up to 8 in	(13 + 8D) μ in	P&W Labmaster™, gage block masters
	Up to 1 in	46 μ in	Mitutoyo laser micrometer, gage block masters
Cylindrical Ring Gages	(0.25 to 12) in	(18 + 7D) μ in	P&W Labmaster™, master rings
Dial/Test Indicators ³	Up to 4 in	(76 + 91L) μ in	Gage blocks or micrometer head
Feeler Gages	Up to 0.05 in	(18 + 7L) μ in	P&W Labmaster™, gage block masters

Parameter/Equipment	Range	CMC ^{2, 4} (\pm)	Comments
Gage Balls	(0.125 to 1) in	$(20 + 7D) \mu\text{in}$	P&W Labmaster TM , gage block masters
Gage Blocks	(0.005 to 12) in	$(3.9 + 3.0L) \mu\text{in}$	P&W Labmaster TM , gage block masters
Height Gages ³	Up to 40 in	$(600 + 41L) \mu\text{in}$	Gage blocks, surface plate
Snap Gages	(0.25 to 8) in	$(18 + 7L) \mu\text{in}$	P&W Labmaster TM , master rings
Bore Gage	Up to 8 in	58 μin	Master rings
Micrometers ³ – Outside	Up to 12 in (< 12 to 60) in	$(55 + 8L) \mu\text{in}$ $(530 + 5L) \mu\text{in}$	Gage blocks
Optical Comparator ³ – Axis Linearity Magnification Angle	12 in (10, 20, 50, 100, 125, 250) x Up to 90°	$(150 + 0.8L) \mu\text{in}$ $(620 + 0.5L) \mu\text{in}$ 0.3°	Glass master scales, angle blocks
Rules & Tape Measures ³	Up to 100 ft	0.6R in	Gage blocks
Thread Plugs – Pitch Diameter (0.3 to 80 TPI) Major Diameter	Up to 4 in Up to 4 in	$(88 + 6D) \mu\text{in}$ $(13 + 8D) \mu\text{in}$	P&W Labmaster TM , gage block masters, thread wire masters <i>TPI = Threads per Inch</i>

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Thread Wires	Up to 0.500 in diameter	(31 + 6D) μin	P&W Labmaster™, gage block masters, plug gage masters
Protractors	Up to 360°	0.08°	Sine plate, gage blocks
Surface Plates ³ –			
Flatness	Up to 144 in	(72 + 0.3L) μin	Planekator
Repeatability	Up to 144 in	49 μin	Repeat-O-Meter

II. Electrical – DC/Low Frequency

Parameter/Equipment	Range	CMC ^{2,5,6} (±)	Comments
DC Voltage – Generate ³	(0 to 330) mV 330 mV to 3.3 V (3.3 to 33) V (33 to 330) V (100 to 1000) V	20 μV/V + 1 μV 11 μV/V + 2 μV 12 μV/V + 20 μV 18 μV/V + 150 μV 18 μV/V + 1.5 mV	Fluke 5522A
DC Voltage – Measure ³	(0 to 100) mV 100 mV to 1 V (1 to 10) V (10 to 100) V (100 to 1000) V (1 to 9) kV	14 μV/V + 3 μV 7 μV/V + 0.3 μV 6 μV/V + 0.05 μV 10 μV/V + 0.3 μV 9 μV/V + 0.1 μV 0.12 %	Hewlett Packard 3458A opt 002 Vitretek 4700
DC Current – Measure ³	(0 to 100) nA 100 nA to 1 μA (1 to 10) μA (10 to 100) μA 100 μA to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A (1 to 10) A	59 μA/A + 0.4 nA 90 μA/A + 0.04 nA 66 μA/A + 0.01 nA 29 μA/A + 0.008 nA 25 μA/A + 0.005 μA 25 μA/A + 5 μA 40 μA/A + 5 μA 120 μA/A + 10 μA 0.29 %	Hewlett Packard 3458A opt 002

Parameter/Range	Frequency	CMC ^{2, 6} (±)	Comments
Capacitance – Generate ³ (220 to 399.9) pF (0.4 to 1.0999) nF (1.1 to 3.2999) nF (3.3 to 10.9999) nF (11 to 32.9999) nF (33 to 109.999) nF (110 to 329.999) nF (0.33 to 1.099 99) μF (1.1 to 3.299 99) μF (3.3 to 10.9999) μF (11 to 32.9999) μF (33 to 109.999) μF (110 to 329.999) μF (0.33 to 1.099 99) mF (1.1 to 3.299 99) mF (3.3 to 10.9999) mF (11 to 32.9999) mF (33 to 110) mF	(10 to 10 000) Hz (10 to 10 000) Hz (10 to 3000) Hz (10 to 1000) Hz (10 to 1000) Hz (10 to 1000) Hz (10 to 1000) Hz (10 to 600) Hz (10 to 300) Hz (10 to 150) Hz (10 to 120) Hz (10 to 80) Hz (0 to 50) Hz (0 to 20) Hz (0 to 6) Hz (0 to 2) Hz (0 to 0.6) Hz (0 to 0.2) Hz	0.41 % + 10 pF 0.39 % + 0.01 nF 0.39 % + 0.01 nF 0.20 % + 0.01 nF 0.19 % + 0.01 nF 0.19 % + 0.01 nF 0.19 % + 0.03 nF 0.56 % + 1 nF 0.26 % + 3 nF 0.20 % + 10 nF 0.31 % + 30 nF 0.35 % + 100 nF 0.35 % + 300 nF 0.35 % + 1 μF 0.35 % + 3 μF 0.35 % + 10 μF 0.60 % + 30 μF 0.43 % + 100 μF	Fluke 5522A
AC Voltage – Generate ³ (1 to 33) mV (33 to 330) mV (0.33 to 3.3) V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (10 to 45) Hz (45 Hz to 10 kHz) (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	0.10 % + 6 μV 0.042 % + 6 μV 0.046 % + 6 μV 0.12 % + 6 μV 0.39 % + 12 μV 0.95 % + 50 μV 0.042 % + 8 μV 0.032 % + 8 μV 0.033 % + 8 μV 0.046 % + 8 μV 0.094 % + 32 μV 0.22 % + 70 μV 0.041 % + 50 μV 0.031 % + 60 μV 0.034 % + 60 μV 0.041 % + 50 μV 0.078 % + 130 μV 0.26 % + 600 μV	Fluke 5522A

Parameter/Range	Frequency	CMC ^{2, 6} (±)	Comments
AC Voltage – Generate ³ (cont)			
(3.3 to 33) V	(10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.24 % + 650 μV 0.031 % + 600 μV 0.037 % + 600 μV 0.045 % + 600 μV 0.098 % + 1.6 mV	Fluke 5522A
(33 to 330) V	45 Hz to 1 kHz (1 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.020 % + 2 mV 0.022 % + 6 mV 0.027 % + 6 mV 0.032 % + 6 mV 0.22 % + 50 mV	
(330 to 1020) V	45 Hz to 1 kHz (1 to 5) kHz (5 to 10 kHz)	0.031 % + 10 mV 0.026 % + 10 mV 0.031 % + 10 mV	
AC Voltage – Measure ³			
Up to 10 mV	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz	0.030 % + 3 μV 0.020 % + 1.1 μV 0.030 % + 1.1 μV 0.10 % + 1.1 μV 0.50 % + 1.1 μV 4.0 % + 2 μV	Hewlett Packard 3458A opt 002
10 mV to 10 V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 2) MHz	0.007 % + 0.4 mV 0.007 % + 0.2 mV 0.014 % + 0.2 mV 0.030 % + 0.2 mV 0.080 % + 0.2 mV 0.30 % + 1.0 mV 1.0 % + 1.0 mV 1.5 % + 1.0 mV	
(10 to 100) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz	0.020 % + 4 mV 0.020 % + 2 mV 0.020 % + 2 mV 0.035 % + 2 mV 0.12 % + 2 mV 0.40 % + 10 mV 1.5 % + 10 mV	

Parameter/Range	Frequency	CMC ^{2, 6} (±)	Comments
AC Voltage – Measure ³ (cont)			
(100 to 1000) V	(1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.040 % + 40 mV 0.040 % + 20 mV 0.060 % + 20 mV 0.12 % + 20 mV 0.30 % + 20 mV	Hewlett Packard 3458A opt 002
(0.7 to 9) kV	(50 to 60) Hz	0.15 % + 0.1 V	Vitretek 4700
AC Current – Generate ³			
(29 to 330) µA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.23 % + 0.1 µA 0.32 % + 0.1 µA 0.16 % + 0.1 µA 0.35 % + 0.15 µA 0.86 % + 0.2 µA 1.7 % + 0.4 µA	Fluke 5522A
(0.33 to 3.3) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.21 % + 0.15 µA 0.13 % + 0.15 µA 0.11 % + 0.1 µA 0.21 % + 0.2 µA 0.51 % + 0.3 µA 1.0 % + 0.6 µA	
(3.3 to 33) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.19 % + 2 µA 0.10 % + 2 µA 0.053 % + 2 µA 0.090 % + 2 µA 0.21 % + 3 µA 0.41 % + 4 µA	
(33 to 330) mA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.19 % + 20 µA 0.10 % + 20 µA 0.053 % + 20 µA 0.12 % + 50 µA 0.23 % + 100 µA 0.46 % + 200 µA	
(0.33 to 1.1) A	(10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.21 % + 100 µA 0.098 % + 100 µA 0.70 % + 1 mA 3.0 % + 5 mA	

Parameter/Range	Frequency	CMC ^{2, 5, 6} (±)	Comments
AC Current – Generate ³ (cont)			
(1.1 to 3) A	(10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.19 % + 100 µA 0.070 % + 100 µA 0.63 % + 1 mA 2.7 % + 5 mA	Fluke 5522A
(3 to 11) A	(45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz	0.080 % + 2 mA 0.12 % + 2 mA 3.0 % + 2 mA	
(11 to 20.5) A	(45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz	0.15 % + 5 mA 0.18 % + 5 mA 3.0 % + 5 mA	
Clamp-On Only			
(20.5 to 150) A (150 to 1000) A	(45 to 65) Hz (45 to 65) Hz	0.42 % 0.44 %	Fluke 5522A w/ 5500A/coil
(20.5 to 150) A (150 to 1000) A	(65 to 440) Hz (65 to 440) Hz	1.2 % 1.2 %	
AC Current – Measure ³			
(0 to 100) µA	(10 to 20) Hz (20 to 45) Hz 45 Hz to 100 Hz 100 Hz to 5 kHz	0.40 % + 0.03 µA 0.15 % + 0.03 µA 0.060 % + 0.03 µA 0.060 % + 0.03 µA	Hewlett Packard 3458A opt 002
(1 to 100) mA	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.40 % + 20 µA 0.15 % + 30 µA 0.060 % + 20 µA 0.030 % + 20 µA 0.060 % + 20 µA 0.40 % + 40 µA 0.55 % + 0.15 mA	
(0.1 to 1) A	(10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz	0.40 % + 200 µA 0.16 % + 200 µA 0.080 % + 200 µA 0.10 % + 200 µA 0.30 % + 200 µA 1.0 % + 400 µA	

Parameter/Range	Frequency	CMC ^{2, 5, 6} (\pm)	Comments
Oscilloscopes ³ –			
Square Wave Signal: (1 kHz Input)			
50 Ω Load @ 1 kHz	1 mV to 6.6 V _{pk-pk}	0.19 % + 40 μ V	Fluke 5522A SC1100
1 M Ω Load @ 1 kHz	1 mV to 130 V _{pk-pk}	0.08 % + 40 μ V	
DC Volt Amplitude:			
50 Ω Load	(0 to 6.6) V	0.19 % + 40 μ V	
1 M Ω Load	(0 to 130) V	0.04 % + 40 μ V	
Leveled Sine Wave: Frequency	(0 to 1100) MHz	2.3 μ Hz/Hz	
Square Wave Signal: (1 kHz Input)			
Leveled Sine Wave Amplitude	50 kHz (Reference)	1.6 % + 300 μ V	
	50 kHz to 100 MHz	2.7 % + 300 μ V	
	(100 to 300) MHz	3.1 % + 300 μ V	
	(300 to 600) MHz	4.7 % + 300 μ V	
	(600 to 1100) MHz	5.4 % + 300 μ V	
Flatness (Bandwidth)	50 kHz to 100 MHz	1.2 % + 100 μ V	
	(100 to 300) MHz	1.6 % + 100 μ V	
	(300 to 600) MHz	3.1 % + 100 μ V	
	(600 to 1100) MHz	3.9 % + 100 μ V	
Time Marker	5 s to 50 ms	(19 + 1000 <i>t</i>) μ s/s	<i>t</i> = time in seconds
	20 ms to 1 ns	1.4 μ s/s	
Rise Time	\geq 300 ps	79 ps	

Parameter/Equipment	Range	CMC ² (\pm)	Comments
Electrical Calibration of RTD Indicators ³ –			
Pt 385, 100 Ω	(-200 to -80) $^{\circ}$ C (-80 to 0) $^{\circ}$ C	0.06 $^{\circ}$ C 0.06 $^{\circ}$ C	Fluke 5522A

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical Calibration of RTD Indicators ³ – (cont)			
Pt 385, 100 Ω	(0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.09 °C 0.1 °C 0.1 °C 0.2 °C 0.3 °C	Fluke 5522A
Pt 385, 200 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.05 °C 0.05 °C 0.07 °C 0.2 °C 0.2 °C 0.2 °C 0.2 °C	
Pt 385, 500 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.06 °C 0.06 °C 0.07 °C 0.1 °C 0.1 °C 0.1 °C 0.2 °C	
Pt 385, 1000 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.04 °C 0.04 °C 0.05 °C 0.06 °C 0.08 °C 0.08 °C 0.09 °C 0.3 °C	
Pt 3916, 100 Ω	(-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.3 °C 0.06 °C 0.06 °C 0.08 °C 0.09 °C 0.1 °C 0.2 °C 0.2 °C 0.3 °C	

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical Calibration of RTD Indicators ³ – (cont)			
Pt 3926, 100 Ω	(-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C	0.06 °C 0.06 °C 0.09 °C 0.2 °C 0.2 °C 0.2 °C	Fluke 5522A
PtNi 385, 100 Ω	(-80 to 0) °C (0 to 100) °C (100 to 260) °C	0.1 °C 0.1 °C 0.2 °C	
Cu 427, 10 Ω	(-100 to 260) °C	0.4 °C	
Thermocouple Simulation ³ –			
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1000) °C	0.52 °C 0.17 °C 0.15 °C 0.17 °C 0.22 °C	
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.33 °C 0.17 °C 0.15 °C 0.18 °C 0.24 °C	
Type K	(-200 to 100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1372) °C	0.59 °C 0.19 °C 0.17 °C 0.26 °C 0.40 °C	
Type R	(0 to 250) °C (250 to 400) °C (400 to 1000) °C (1000 to 1767) °C	0.63 °C 0.43 °C 0.37 °C 0.43 °C	
Type S	(0 to 250) °C (250 to 1000) °C (1000 to 1400) °C (1400 to 1767) °C	0.52 °C 0.40 °C 0.39 °C 0.48 °C	

Parameter/Equipment	Range	CMC ² (±)	Comments
Thermocouple Simulation ³ – (cont)			
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.69 °C 0.27 °C 0.19 °C 0.16 °C	Fluke 5522A

III. Mechanical

Parameter/Equipment	Range	CMC ^{2, 4, 5, 8} (±)	Comments
Torque – Measuring Devices ³	(0.021 to 250) lbf·ft	0.054 % Applied Load	Wheels & weights
Torque ³ – Wrenches	Up to 5 lbf·ft (5 to 1000) lbf·ft	0.96 % full scale 0.66 % full scale	Torque transducers
Pressure ³ – Measuring Equipment	Up to 10 000 psi	0.07 %	Comparison to master pressure gauge
Force ³ – (Tension & Compression)			
Gages	Up to 1000 lbf	1.7R lbf	Verification w/ASTM class 6 weights
Transducers	Up to 1000 lbf (1000 to 50 000) lbf Up to 500 000 lbf (Compression only)	0.06 % full scale 0.05 % full scale 0.09 % full scale	Load cell & meter
Analytical Balances ³	(0 to 200) g	0.59 mg	Verification w/ Class 1 weights

Parameter/Equipment	Range	CMC ^{2, 4, 5} (±)	Comments
Balances ³	(200 to 1000) g (1000 to 2000) g (2000 to 10 000) g (10 000 to 20 000) g (20 000 to 40 000) g	0.002 % 0.002 % 0.002 % 0.002 % 0.002 %	Verification w/ Class 1, 3 & F weights
Mass, Fixed Points	(1, 2, 3, 5) mg (10, 20, 30, 50) mg (100, 200, 300) mg 500 mg 1 g 2 g (3, 4, 5) g (10, 20) g (30, 40) g 50 g 100 g 200 g 300 g (400, 500) g 1 kg (2, 3, 4) kg 5 kg 10 kg 20 kg 25 kg (1/32, 1/16, 1/8) oz (1/4, 1/2) oz (1, 2) oz 4 oz 8 oz 0.001 lb 0.002 lb 0.005 lb 0.01 lb 0.02 lb 0.05 lb 0.1 lb 0.2 lb 1 lb 2 lb (3, 4, 5) lb 10 lb (20, 25) lb 50 lb	0.006 mg 0.006 mg 0.007 mg 0.007 mg 0.01 mg 0.01 mg 0.01 mg 0.02 mg 0.10 mg 0.10 mg 0.10 mg 0.15 mg 20 mg 20 mg 20 mg 22 mg 22 mg 270 mg 250 mg 420 mg 0.000 004 oz 0.000 005 oz 0.000 017 oz 0.000 017 oz 0.000 17 oz 0.000 000 22 lb 0.000 000 15 lb 0.000 000 2 lb 0.000 000 15 lb 0.000 000 22 lb 0.000 000 31 lb 0.000 000 57 lb 0.000 000 75 lb 0.000 021 lb 0.000 013 lb 0.000 035 lb 0.000 044 lb 0.0006 lb 0.000 93 lb	Comparison to Class 1 standard weights

Parameter/Equipment	Range	CMC ^{2, 4, 5} (±)	Comments
Scales ³	(0 to 200 000) lb	0.02 %	Verification w/ Class F weights
Indirect Verification of Rockwell Hardness Testers ³	HRC Low Medium High HRBW Low Medium High	0.69 HRC 0.94 HRC 1.6 HRC 2.2 HRBW 0.66 HRBW 0.66 HRBW	Master blocks
Indirect Verification of Rockwell A,N,T Hardness ³	HRA Low Mid High HR15N Low Mid High HR30N Low Mid High	0.36 HRA 0.61 HRA 0.31 HRA 0.67 HR15N 0.58 HR15N 0.42 HR15N 0.62 HR30N 0.62 HR30N 0.68 HR30N	Master blocks
Indirect Verification of Vickers Hardness, Knoop Hardness ³	Vickers, ≤ 1 kg (100 to 240) HV (241 to 600) HV (600 to >650) HV	3.5 HV 8.6 HV 11 HV	Master blocks
Tachometers (Non-Contact) ³	(1 to 99 999) rpm	0.000 29 % + 0.58R	Fluke 5522A w/ LED emitter
RPM (Non-Contact) – Measure ³	(6 to 99 999) rpm	0.033 % + 0.58R	Shimpo DT-2100 tachometer

IV. Thermodynamics

Parameter/Equipment	Range	CMC ^{2, 5, 8} (±)	Comments
Temperature – Measure ³	(-200 to 0) °C (0 to 350) °C	3.6 °C 1.7 °C	Fluke 744, SLE type T thermocouple
	(350 to 704) °C (704 to 1250) °C	3.3 °C 5.8 °C	Fluke 744, SLE type K thermocouple
	(-35 to 0) °C (0 to 150) °C (150 to 375) °C	0.13 °C 0.13 °C 0.14 °C	1560 black stack, 2560 probe module, SPRT probe
Temperature – Thermometers, Temperature Probes, Measuring Equipment ³	(-35 to 0) °C (0 to 150) °C (150 to 375) °C	0.13 °C 0.13 °C 0.14 °C	1560 black stack, 2560 probe module, SPRT probe
Infrared Temperature Devices	0 °C (35 to 100) °C (100 to 200) °C (200 to 350) °C (350 to 500) °C	0.8 °C 1.0 °C 1.5 °C 2.7 °C 3.5 °C	Ice bath Fluke 4181 blackbody calibrator
Relative Humidity – Measure	(10 to 90) % RH (90 to 98) % RH	1.8 % RH 2.6 % RH	Vaisala MI70 w/ HMP77 probe

V. Time & Frequency

Parameter/Equipment	Range	CMC ² (±)	Comments
Stopwatches & Timers ³	0.1 s to 24 hr (+10 to -10) s/day	0.068 s 0.07 s/day	HP 53131A opt 010 Timometer 4500
Frequency – Measuring Equipment ³	(0.01 to 119.99) Hz (120.0 to 1199.9) Hz (1.200 to 11.999) kHz (12.00 to 119.99) kHz (120.0 to 1199.9) kHz (1.200 to 2.000) MHz	0.01 % + 5 µHz 0.01 % + 5 µHz 0.01 % + 5 µHz 0.01 % + 5 µHz 0.07 % + 5 µHz 0.2 % + 5 µHz	Fluke 5522A

- ¹ This laboratory offers commercial calibration service and field calibration service.
- ² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.
- ³ Field calibration service is available for this calibration. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g., resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.
- ⁴ In the statement of CMC, R is the numerical value of the resolution of the device under test in RPM or in pounds-force or in microinches, and L is the numerical value of the nominal length of the device measured in inches. D is the numerical value of the nominal diameter of the device measured in inches.
- ⁵ In the statement of CMC, percentages are percentage of reading, unless otherwise indicated.
- ⁶ The stated measured values are determined using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure or generate the measured value in the ranges indicated. CMCs are expressed as either a specific value that covers the full range or as a fraction/percentage of the reading plus a fixed floor specification.
- ⁷ This scope meets A2LA's *P112 Flexible Scope Policy*.
- ⁸ The type of instrument or material being calibrated is defined by the parameter. This indicates the laboratory is capable of calibrating instruments that measure or generate the values in the ranges indicated for the listed measurement parameter.



Accredited Laboratory

A2LA has accredited

GRAND RAPIDS METROLOGY

Grand Rapids, MI

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCCL Z540-1-1994 and R205 – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 18th day of November 2021.

A blue ink signature of Mr. Trace McInturff, written over a horizontal line.

Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 1489.01
Valid to November 30, 2023
Revised October 17, 2023

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.